

Search Notes

Application/Control No.

10/700,279

Examiner

Tamai IE Karl

Applicant(s)/Patent under
Reexamination

YAN ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	309, 40mm		
359	223-226		
	291	06/11/05	bu

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR